

## NEW AND/OR INTERESTING IN MICROSCOPY

*It is with much sadness that we advise that Morton D. "Mort" Maser, Executive Secretary to Council of both the Microscopy Society of America and the Histochemical Society, died unexpectedly on Saturday, March 18, 1995 as the result of a heart attack.*

*Memorial services celebrating his life are being planned for the summer months. Details will be announced as they are finalized.*

*In memory of Mort, his family is establishing the Morton D. Maser Scholarship Fund. Contributions can be sent to: Larry Maser, P.O. Box EM, Woods Hole, MA 02543. Please designate your gift to the Morton D. Maser Scholarship Fund*

• The Microscopical Society of Canada has announced its 22nd Annual Meeting to be held on June 4-7, 1995, at the University Centre Building, University of Ottawa, Ottawa. A varied and interesting scientific program has been planned and will consist of a combination of interdisciplinary symposia presented by speakers from around the world, separate physical and biological symposia, oral and poster presentations, workshops on TEM specimen preparation of materials and cryo-SEM specimen preparation and X-ray analysis, and commercial exhibits.

For information on the program contact Jim Corbett, University of Waterloo, at tel.: (519)885-1211.

For information on registration contact Shea Miller or Paula Allan-Wojtas, Agriculture and Agri-Food Canada, at tel.: (613)957-4347, ext. 7908.

• On 2 March 1995, Thermo Instruments Systems (the current parent of NORAN Instruments) announced that it has signed a purchase agreement with Fisons, plc to acquire the Scientific Instruments Division of Fisons (the current parent of Kevex and VG Instruments) for 202 million British pounds sterling, subject to a post-closing agreement.

As would be expected, this action was an active topic of discussion at Pittcon between both the employees and product users of NORAN and Kevex. The only rumor-of-possible-value was that it seemed unlikely that the two companies, under common ownership, will continue to compete with each other. The remaining options might then be:

- 1) The merging of the resources, products, etc. of both NORAN and Kevex into one company. Or, of you like, the acquisition of major talent, products, etc. of one company by the other.
- 2) The breakout and sale of one of the companies to another party. There seems to be a rumor that there is at least one outside company interested in purchasing "one" of the two companies.

• The American Vacuum Society's (AVS) Education Committee has developed an interactive HyperCard® stack, an interactive program, designed to help students at all levels learn the fundamental principles of vacuum science and technology. The stack is divided into four sections; What is Vacuum, Vacuum Pumps, Vacuum Gauges and Applications.

The cost of the HyperCard stack is \$15.00. For more information, or to place an order, contact Angela Mulligan, AVS, 120 Wall Street, 32nd Floor, New York, NY 10005. Tel.: (212)248-0200, Fax: (212)248-0245.

## NEW PRODUCT NEWS

• Leica Inc. is pleased to introduce the newest member of the DM family of microscopes, the LEICA DM C Comparison Microscope. The LEICA DM C is ideally equipped for any forensic examination. This instrument provides clear-cut evidence by optically magnified "side by side" or superimposition of two objects in one field of view, allowing direct visual comparison of sizes of object structures or spaces. This instrument was developed to meet the demand for new illumination and imaging techniques for the increasing number of investigations of traces on plastics as opposed to metals. Coaxial illumination, using Leica's proven Macrozoom objectives, is the only technique capable of producing high-contrast, flare-free images of opalescent or very shiny plastic surfaces. The modular design of the LEICA DM C Comparison Microscope allows universal application potential due to its modular system. This modular design of the LEICA DM C makes it an all-purpose tool for...

- **Forensic labs** - The zoom objectives enable continuous matching of the magnifications to allow for firearm traces on fired ammunition parts, comparison of objects bearing toolmarks, comparisons between original and forged documents, currency, stamps, and seals;
- **Security Printing Works** - Quality assurance of printed matter;
- **State-Operated Mints** - Quality assurance of currency;
- **Banks** - Authenticity testing of modern and antique currency made of precious metals;
- **Industry** - Quality assurance in imaging of surface structures.

The LEICA DM C features five illumination units and its capable of observation and documentation, simultaneously with photo and video camera.

For further information regarding the LEICA DM C Comparison Microscope contact Leica Inc., 111 Deer Lake Road, Deerfield, Illinois, USA, Telephone toll-free (800)248-0123, Fax (708)405-0030. **Circle Reader Inquiry #22**

### ElectroImage - #1 in DIGITAL MICROSCOPY

- The EICAS-9400 - Add digital capability to video microscopy. A one monitor solution that includes image analysis, removable archiving, and image database.
- The EICAS-D - Capture images 2700 x 3380, display images 1600 x 1200 in 24 bits. Add image analysis, built-in recordable CD-ROM, and image database. A simple to use, light microscope digitization system capable of handling large images inexpensively.
- The ORION - Digitize your analog SEM or upgrade your digital SEM. ORION features include: image capture up to 8K x 8K, display modes, up to 1600 x 1200, and amazingly noise-free averaged or integrated images.

**Call (516)773-4305 for more information. Circle Reader Inquiry #20**

• M.E. Taylor Engineering introduces the MTP-1 Magnetically Driven Twin-Jet Electropolisher. The MTP-1 is used to produce thin foils, electrochemically, for viewing in the TEM.

Based on the research of Dr. Wang Yongrui, Shanghai Jiao Tong University, the MTP-1 offers features not generally available. Electrolyte is pumped through the twin jets by a magnet pump. The motor for the pump is in a scaled compartment separate from the working chamber; so it is never exposed to a harsh environment. The light and sensor are built into the jets. Since they are coaxial, pre-alignment for the smallest size pinhole is assured.

Another unique feature of the MTP-1 is the ability to cool the electrolyte with a liquid nitrogen heat exchanger. Other types of cooling are also built-in. For further information, contact M.E. Taylor Engineering, Inc., Brookeville, MD, (301)774-6246, Fax: (301)774-6711. **Circle Reader Inquiry #21**

☛ The SM-520 Field Emission SEM introduced by **Topcon Technologies, Inc.** features Field Emission Performance at LaB6 prices. The SM-520 is equipped with a sample airlock and a large specimen stage that will accommodate 6 inch diameter samples. A full featured image processing system that can digitize images up to 2K by 2K is standard. Image processing includes frame averaging up to 256 frames, unlimited image storage, an image database, and a graphical user interface. Tel.: ((201)261-5410, Fax: (201)262-1504.

☛ **Spectra-Tech Inc.** introduces the InspectIR, a unique FT-IR microsampling accessory that combines Spectra-Tech's exclusive ATR and external reflection microanalysis capabilities with the latest advances in optical design and digital video imaging to produce a microsampling accessory that can be used by anyone in the laboratory to acquire excellent quality spectral data from samples as small as 50 microns easily and quickly. The InspectIR's built-in ease of use permits analysis of almost any sample with no preparation. The External Reflection mode is ideal for analyzing coatings, films, lubricants and contaminants on metallic surfaces. The ATR mode is optimum for analyzing most infrared absorbing materials includ-

ing those that have low reflectivity such as polymers, pharmaceuticals, rubber, contaminants, fibers, paper and forensic samples. Sample analysis is as easy as bringing the specimen in contact with the ATR sampling crystal and analyzing. The InspectIR provides a color video image of the sample on the spectrometer's computer monitor. The video image can be stored and manipulated without exiting from the FT-IR software. Tel.: (203)926-8998, Fax: (203)926-8909.

☛ **TopoMetrix** presented the results of several users of its Aurora™ Near-Field Scanning Optical Microscope - including nanoscale spectroscopy and *single molecule detection*. TopoMetrix' new Accurex™ Scanning Probe microscope with TrueMetrix™ scanning linearization handles samples up to 14 inches in diameter, and its new scanning thermal microscope produces surface temperature maps with nanoscale resolution and obtains thermal conductivity data on microscopic structures. Layered Imaging™, a new technique, maps the magnetic and electric fields above a sample's surface and surface compliance and adhesion. TopoMetrix Corporation, Tel.: (408)982-9700, Fax: (408)982-9751.

## COMING EVENTS

- ✓ April 4/7 '95: **Ultramicrotomy in Materials Science.** RMC, Tucson, AZ. Bob Chiovetti: Tel.: (602)889-7900, Fax: (602)741-2200.
- ✓ April 4/7 '95: **Expoanalitica + Biociencia** Madrid, Spain. Tel.: +343 423 31 01, Fax: +343 423 63 48.
- ✓ April 6/7 '95: **FT-IR Microscopy Training Course.** (Spectra-Tech, Inc.). Shelton, CT. Debbie Esposito: Tel.: (800)243-9186, (203)926-8998 (CT)
- ✓ April 17/21 '95: **Spring MRS Meeting.** San Francisco, CA. Mary Kaufold: (412)367-3036.
- ✓ April 18 '95: **Light Element EDS Workshop** Univ. of Minnesota, Nolte Ctr., Minneapolis, MN. Gib Ahlstrand: Tel.: (612)625-8249, eMail: giba@puccini.crl.umn.edu
- ✓ April 18/20 '95: **Focus On Microscopy 95.** Taipei, Taiwan. P.C. Cheng: (716)645-3868.
- ✓ April 24/29 '95: **22nd International Conference on Metallurgical Coatings and Thin Films (AVS).** San Diego, CA. Mary Gray. Tel.: (301)870-8756, Fax: (301)645-1426.
- ✓ May 5/31 '95: **Workshops: Site/area-Specific Cross-sectioning and Materials Ultramicrotomy.** (AMC Group). Several locations. (602)949-4203. Fax: (602)947-7615.
- ✓ May 6/11 '95: **Food Structure Annual Meeting** (Scanning Microscopy International). Houston, TX. Dr. Om Jahari. Tel.: (708)529-6677. Fax: (708)980-6698.
- ✓ May 15/17 '95: **TEM Specimen Preparation** (Gatan). Pleasanton, CA. Chris Byrne: (510)463-0200.
- ✓ May 16/18 '95: **Computer-Assisted Image Analysis and Measurement** (North Carolina State Univ.). Raleigh, NC. Belinda Niedwick: Tel.: (919)515-2261, Fax: (919)515-7614.
- ✓ May 18/20 '95: **Cryo-TEM of Colloidal Materials** (CIE, Univ of MN). Minneapolis, MN. Beth Trend: (612)624-1365.
- ✓ May 20/24 '95: **EUCHEM Conference on Electron Microscopy in Solid State Science.** Lund, Sweden. Swedish Nat'l Committee for Chemistry. Tel: +46-(0)8-4115280
- ✓ May 29/June 23 '95: **Introduction to the Meiofauna** (Univ of S. Carolina short course). Georgetown, SC. Kitty Harper. (803)777-2692
- ✓ June 4/7 '95: **22nd Annual Meeting of the Microscopical Society of Canada.** Univ of Ottawa. Shea Miller, Tel.: (613)957-4347 X-7709, Fax: (613)943-2353.
- ✓ June 6/9 '95: **3rd Annual Symposium on AFM & STM** (US Army Natick RD&E Ctr. Natick, MA. Samuel Cohen: (508)651-4578
- ✓ June 7/9 '95: **Confocal Microscopy and Quantitative Image Analysis** (Geo. Washington Univ. 21st Annual Program). Washington, DC. Fred G. Lightfoot (202)994-2881, Fax: (202)994-8885.
- ✓ June 12/22 '95: **Lehigh Microscopy Courses - SEM, X-ray Analysis, AEM, AFM.** Bethlehem, PA. Prof. David B. Williams, Tel.: (610)758-5133, Fax: (610)758-4244.
- ✓ June 15/17 '95: **Microwave Workshop.** (Ted Pella, Inc.) California State Univ, Chico, CA. Rick Giberson: Tel.: (800)237-3526 (US) or (800)637-3526 (CA), Fax: (916)243-3761.
- ✓ June 26/30 '95: **Congres "Trinoculaire" de Microscopies Electroniques.** Joint Meeting SBM, SFME, SGOEM. Details: P.A. Buffat, EPFL-CIME. Fax: +41 21 693 44 01, eMail: philippe.buffat@cime.cpl.ch
- ✓ June 26/30 '95: **Computer Simulation and Processing of HRTEM Images.** NCEM, Lawrence Berkeley Lab., Berkeley, CA. Michael A. O'Keefe, eMail: MAOK@LBL.GOV.
- ✓ June 26/30 '95: **11th Annual Short Course on Molecular Microspectroscopy.** Oxford, OH. (513)529-2873
- ✓ June 10/13 '95: **INTER/MICRO '95.** McCrone Research Institute. Chicago, IL. Nancy Daerr, Tel.: 312)842-7100, Fax: (312)842-1078
- ✓ July 3/6 '95: **CYTO 95 - The Application of the Microscope in Life Sciences.** (RMS). Univ. of Southampton. Tel.: 0865 248768, Fax: 0865 791237
- ✓ July 10/Aug 4 '95: **Estuarine Fish Ecology** (U. of S. Carolina short course). Georgetown, SC. Kitty Harper: (803)777-2692.
- ✓ August 6/11 '95: **Microbeam Analysis Society (MAS) National Meeting.** Breckenridge, CO. Gregory Meeker, Tel.: (303)236-1081, Fax: (303)236-1414.
- ✓ August 13/17 '95: **Microscopy Society of America/Histochemical Society Annual Meeting.** Kansas City, MO. (800)538-3672, Fax: (508)548-9053.
- ✓ August 29/Sept 2 '95: **14th International Congress on X-ray Optics & Microanalysis.** GuangZhou, China. Tel.: 8620-777-5213, Fax: 8620-777-5791.
- ✓ Sept 2/6 '95: **3rd Interamerican Congress of Electron Microscopy.** Caxambu MG, Brazil. Elliot Kitajima, Tel.: 55-61-3482424, Fax: 55-61-3499094.
- ✓ Sept 26/Oct 2 '95: **14th International EM Congress.** Cancun, Mexico. Miguel Jose Yacamán. Tel.: 525-570-85-03, Fax: 525-570-85-03.
- ✓ Sept 26/30 '95: **OIM Academy - EBSP & Orientation Imaging Microscopy.** (TSL, Inc.). Provo, Utah. David Dingley: Tel: (801)344-8990, Fax: (801)344-8997.
- ✓ Oct 9/13 '95: **Scanning Electron Microscopy and X-Ray Microanalysis for the Materials Scientist.** (SUNY - Inst. of Materials Science). New Paltz, NY. Dr. A.V. Patsis: Tel.: (914)257-3800, Fax: (914)255-0978.
- ✓ Oct 16/20 '95: **AVS Annual National Symposium.** Minneapolis, MN. Tel.: (212)248-0200, Fax: (212)248-0245.
- ✓ Oct 24/27 '95: **Microtomy for EM and Light Microscopy Workshop** (RMC and Univ. of Arizona). Tucson, AZ. Bob Chiovetti: (520)889-